

In the United States Patent and Trademark Office

In re the application of
Lee D. Whetsel

TI-25300.2

Serial No.: 10/806,539

Art Unit: 2138

Filed: March 23, 2004

Examiner: S. Radosevich

Title: Probeless Testing of Pad Buffers on Wafer

Amendment D Under 37 CFR 1.116

February 15, 2007

Asst. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to the Examiner's Action of 09/25/2006, please
amend this application as follows: